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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/629,542	KIM ET AL.	
Examiner	Art Unit	
Dennis-Doon Chow	2629	

	SEARCHED			
Class	Subclass	Date	Examiner	
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	87			

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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